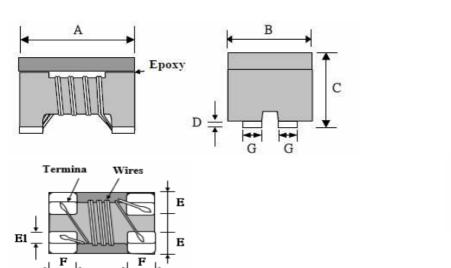


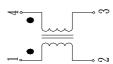
HIGH TEMP AEC-Q200 INDUCTORS — EF4P3225ERQ1 SERIES

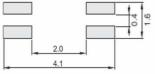


FEATURE

- 1. For automobile signal line
- 2. Same as TDK ACT1210 type
- 3. AEC-Q200 Qualified.
- Applications
- 1. CAN-BUS, FlexRay, etc
- Shape and Dimension and Schematics and Land Patterns(mm)







 $A{=}3.20{\pm}0.20 \text{m/m} \; ; \; B{=}2.5{\pm}0.20 \text{m/m} \; ; \; C{=}2.50 \text{m/m} \; MAX \; ; \; D{=}0.08 \text{m/m} \; typ. \; ; \; E{=}1.00 \text{m/m}$

 $E1=0.50 m/m \ typ. \ ; F=0.60 m/m \ typ. \ ; G=0.50 m/m \ typ.$

● <u>Specification</u> Dimension in m/m

PART NO.	Common Mode INDUCTANCE (uH) (+50%/-30%)	Imped	on mode lance at MHz (Ω)typ.	Rated Current (mA)	Rated Voltage (Vdc)	Insulation Resistance (M ohm)	Withstand Voltage (Vdc)	DC Resistance (max.) (ohm)
EF4P3225ERQ1-110	11uH at 100KHz	300	550	300	80	10 min	125	0.40
EF4P3225ERQ1-220	22uH at 100KHz	500	1100	250	80	10 min	125	0.50
EF4P3225ERQ1-510	51uH at 100KHz	1000	2600	200	80	10 min	125	0.70
EF4P3225ERQ1-101	100uH at 100KHz	2200	5100	150	80	10 min	125	1.50

Note1. Measurement ambient temperature of electrical: at 20°C

Note2. Test equipment: HP4291A

Note3.Packaging: Taping; Quantity: 2000 Pieces/reel



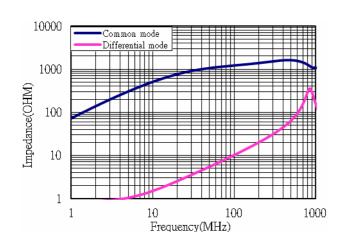
HIGH TEMP AEC-Q200 INDUCTORS - EF4P3225ERQ1 SERIES

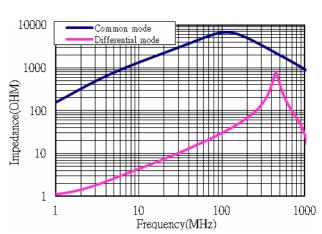


EF4P3225ERQ1 (Impedance VS Frequency)

EF4P3225ERQ1-110

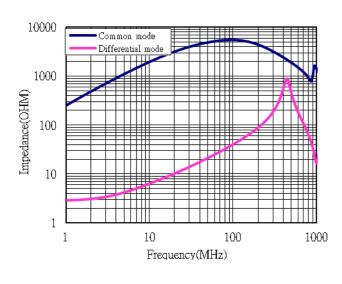
EF4P3225ERQ1-220

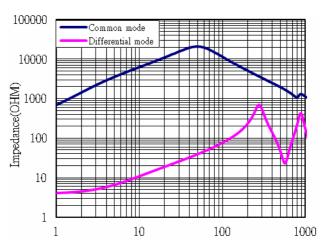




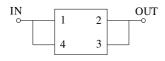
EF4P3225ERQ1-510

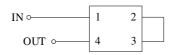
EF4P3225ERQ1-101





Test circuit





COMMON MODE

NORMAL MODE



HIGH TEMP AEC-Q200 INDUCTORS — EF4P3225ERQ1 SERIES



GENERAL CHARACTERISTICS

- 1. Operating temperature range: -40 TO + 125°C (Includes temperature when the coil is heated)
- 2. High temperature exposure(storage) refer MIL-STD-202 Method 108: 1000 hrs at rated operating temperature(e.g. 125°C). Part can be stored for 1000 hrs @125°C. Unpowered. Measurement at 24±4 hours after test conclusion.
- 3. Temperature cycling refer JESD22 Method JA-104: 1000 cycles(-55 TO + 125°C). Measurement at 24±4 hours after test conclusion. 30 min maximum dwell time at each temp. extreme. 1 min. maximum transition time.
- 4. Biased Humidity refer MIL-STD-202 Method 103: 1000 hours 85℃/85%RH. Unpowered. Measurement at 24±4 hours after test conclusion.
- 5. Operational Life refer MIL-PRF-27: 1000 hrs. at 125 ℃ tested. Measurement at 24±4 hours after test conclusion.
- 6. External Visual refer MIL-STD-883 Method 2009: Inspect device construction, marking and workmanship.
- 7. Physical Dimension refer JESD22 Method JB-100: Verify physical dimensions to the applicable device detail specification.
- Resistance to Solvents refer MIL-STD-202 Method 215: Add aqueous wash chemical OKEM clean or equivalent.
- 9. Mechanical Shock refer MIL-STD-202 Method 213: Figure 1 of Method 213. Condition C.
- 10. Vibration refer MIL-STD-202 Method 204: 5g;s for 20 minutes, 12 cycles each of 3 orientations. Test from 10-2000 Hz.
- 11. Resistance to soldering Heat refer MIL-STD-202 Method 210: Condition B No pre-heat of samples. Single wave solder-procedure 2 for SMD and procedure 1 for leaded with solder within 1.5mm of device body.
- 12. ESD refer AEC-Q200-002 or ISO/DIS 10605: Direct contact discharge 2kV.
- 13. Solderability refer J-STD-002: For both Leaded & SMD. Magnification 50X. Conditions: Leaded, Method A@235℃, category 3; SMD, a)Method B, 4hrs@125℃ dry heat @235℃, b)Method B@215℃ category 3., c)Method D category 3@260℃
- 14. Electrical Characterization refer spec: Show Min, Max Mean and Standard deviation at room from Min and Max temperature.
- 15. Flammability refer UL-94: V-0 or V-1 Acceptable.
- 16. Board Flex refer AEC-Q200-005: 60 sec minimum holding time.
- 17. Terminal Strength(SMD) refer AEC-Q200-006
- 18. Reflow profile recommend:

Lead-free heat endurance test

T(°C)
300
250
200
150
100
50
0 60 120 180 240 300

Lead-free the recommended reflow condition

